SPRINT TESTING SOLUTIONS

EXPEDITE. ANALYSE. DEVELOP.

One Stop Solution For All Your Testing Needs

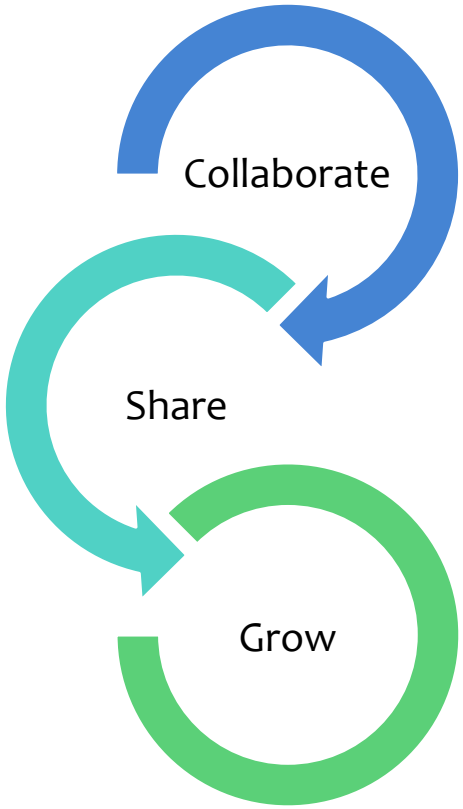
info@sprinttesting.com

www.sprinttesting.com

Introduction

- Sprint Testing Solutions started in 2012 as a consultancy for material testing
- Bridging the gap between research and testing
- Presence all across India
- Diverse Testing and Analysis Capabilities

Methodology



- Collaboration is our strength, we understand your requirements and offer you the best possible option
- Share your needs with us and we assure best solution
- We support in your growth by helping in your research and development

Services offered

Sprint Testing Solutions

- Material Testing
- Raw Material Validation
- Data Analysis
- Consultancy
- Instrument Training

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Sectors

Automotive

Manufacturing

Pharma

Energy

Chemical

Academic Research

University Collaboration

The Sprint Team

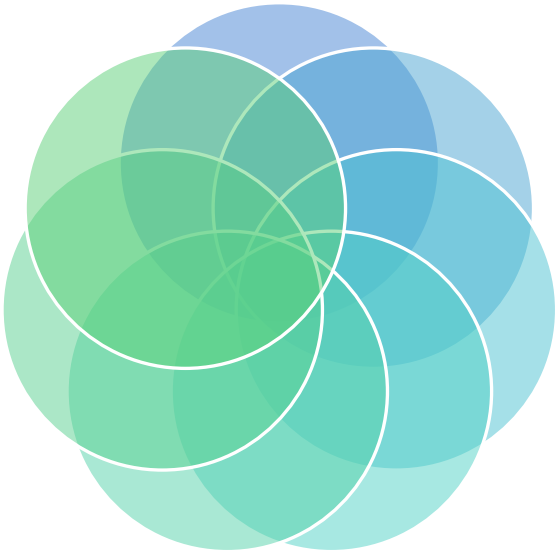
- Industry Professionals
- Experienced material scientist and engineers with expertise in specialized areas.
- Global exposure and from reputed institutes
- Experts with strong industry and research experience providing customers quality analysis on critical samples.
- Subject Specific Consultants

Why Choose Us

Speed of service

Commitment for customer satisfaction

Test Customization to suit your needs



Cost effectiveness

Conformance with required standards

Interpretation of test data

Data Consistency and Quality

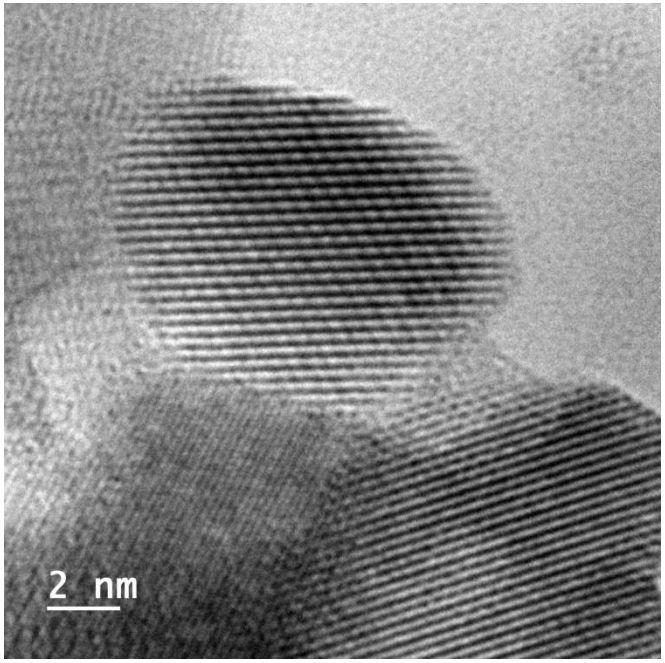
Working principle

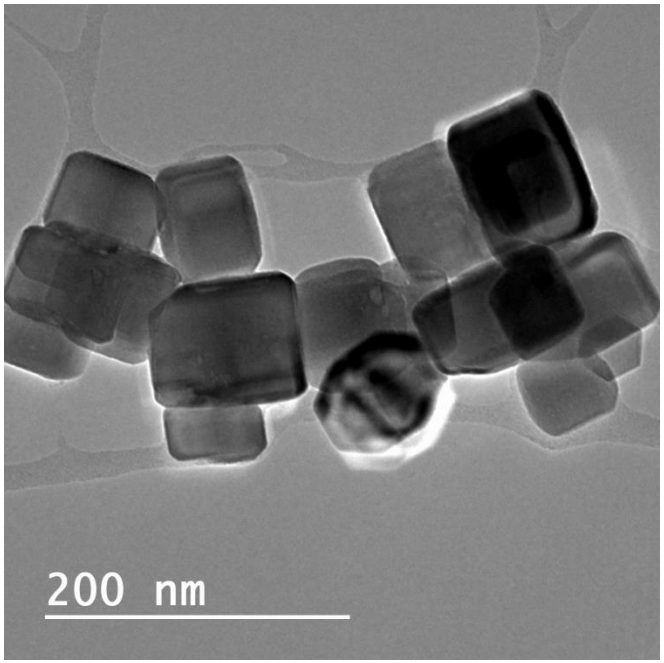
- Confidentiality
- Secure data sharing
- Non Disclosure Agreement
- Anonymity of sources
- Reliable data on calibrated instruments
- Interpretation by experts

Testing Services

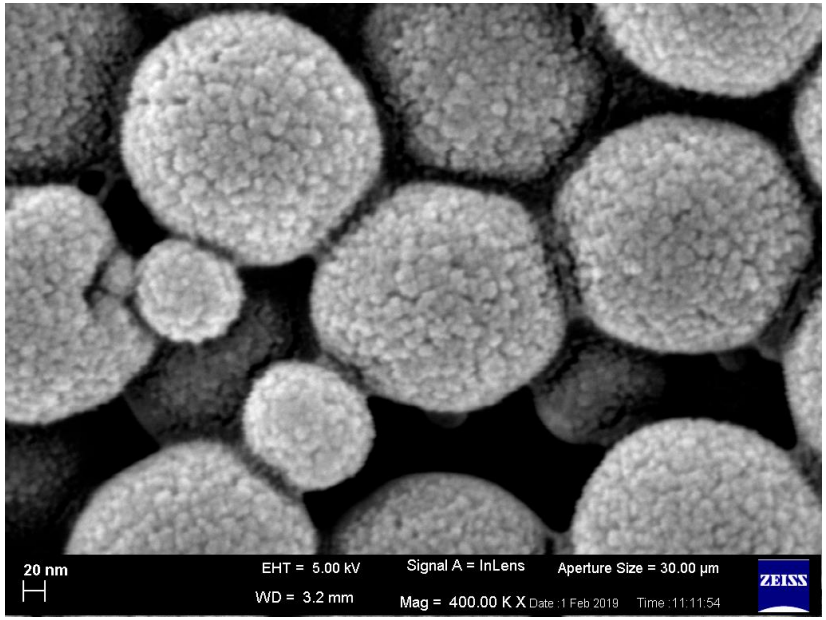
- FE-SEM
- TEM and HR-TEM
- XPS
- XRD
- AFM
- Particle Size
- FTIR
- Raman
- NMR
- And several more (check our website for more details)

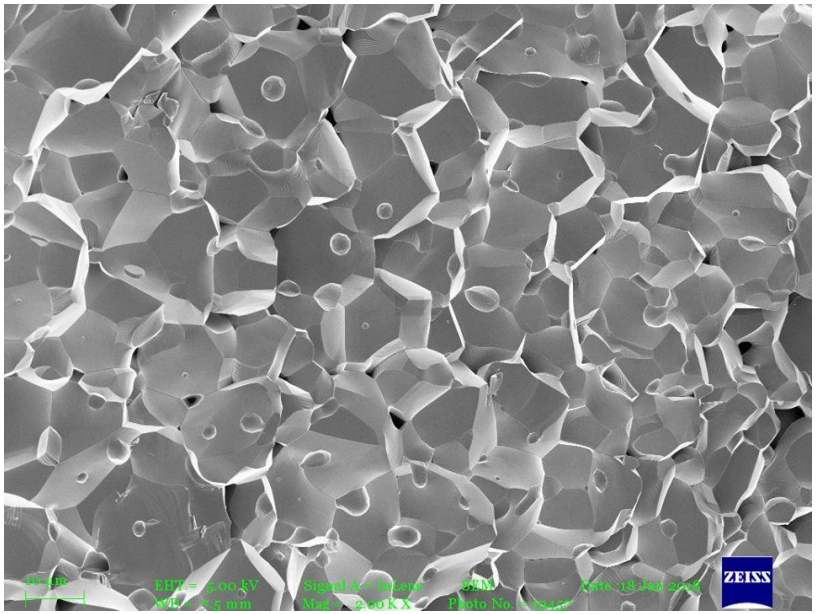
Sample Data: TEM



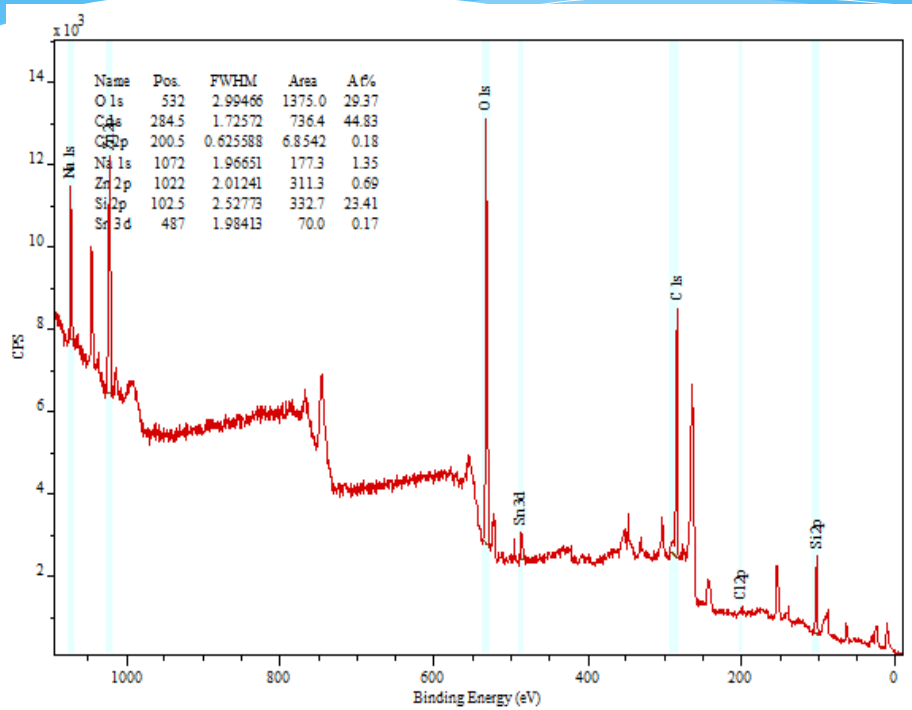


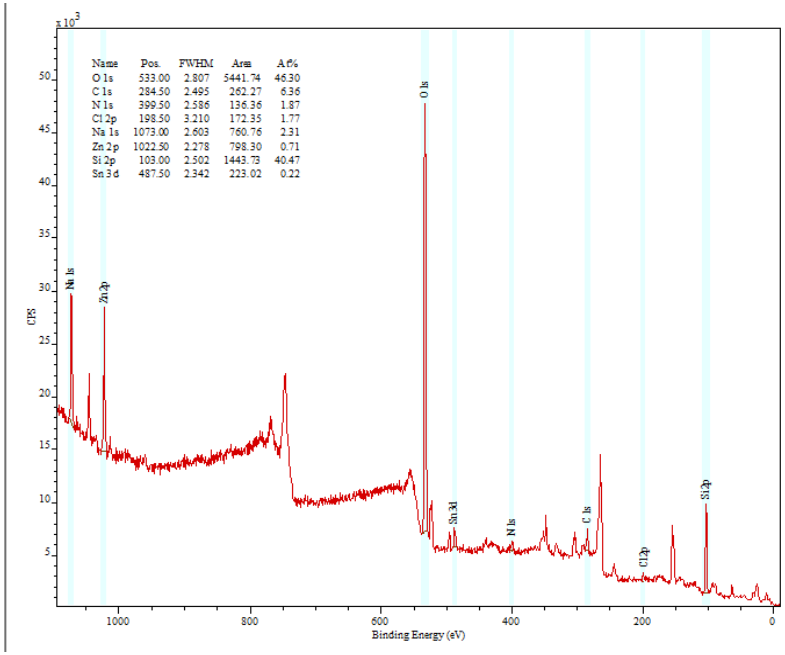
Sample Data: FESEM





XPS





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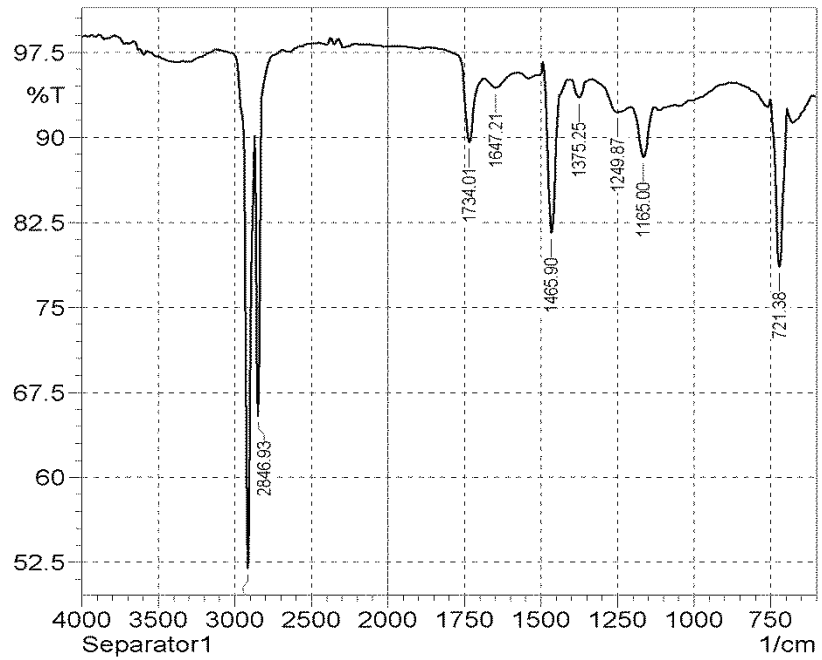
FTIR



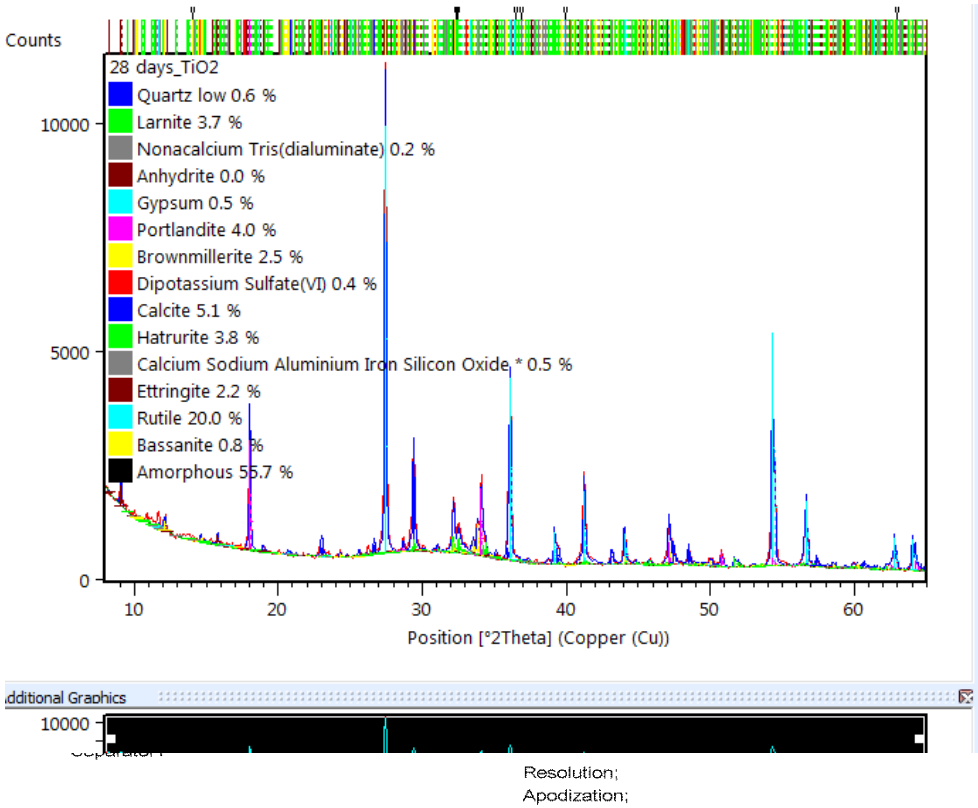
SHIMADZU

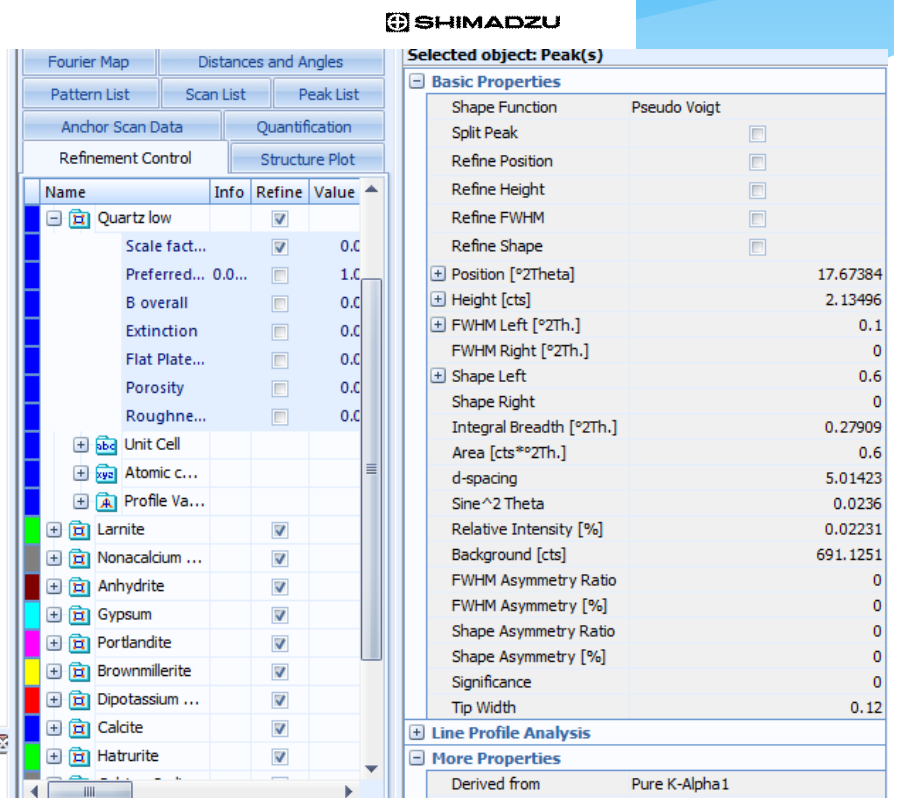
No.	Peak	Intensity	Corr. Inte	Base (H)	Base (L)	Area	Corr. Are
1	721.38	78.572	14.156	750.31	698.23	3.571	1.872
2	1165	88.237	4.427	1207.44	1130.29	3.259	0.706
3	1249.87	92.191	1.286	1332.81	1209.37	3.664	0.291
4	1375.25	93.498	1.592	1402.25	1334.74	1.679	0.205
5	1465.9	81.597	13.532	1492.9	1440.83	2.852	1.72
6	1647.21	94.387	0.98	1685.79	1583.56	2.299	0.221
7	1734.01	89.541	6.37	1867.09	1685.79	3.432	0.895
8	2846.93	65.42	25.623	2868.15	2746.63	6.392	3.276
9	2914.44	51.957	40.438	3012.81	2870.08	12.133	8.146

Comment;
Separator1

Date/Time; 8/31/2015 3:29:58 PM
No. of Scans;
Resolution;
Apodization;

XRD


Counts
28 days_TiO2
Quartz low 0.6 %
Larnite 3.7 %
Nonacalcium Tris(dialuminate) 0.2 %
Anhydrite 0.0 %
Gypsum 0.5 %
Portlandite 4.0 %
Brownmillerite 2.5 %
Dipotassium Sulfate(VI) 0.4 %
Calcite 5.1 %
Hatrurite 3.8 %
Calcium Sodium Aluminium Iron Silicon Oxide * 0.5 %
Ettringite 2.2 %
Rutile 20.0 %
Bassanite 0.8 %
Amorphous 55.7 %
10000
5000
0
10
20
30
40
50
60
Position [°2Theta] (Copper (Cu))
Additional Graphics
10000
Resolution;
Apodization;


SHIMADZU
Fourier Map
Distances and Angles
Pattern List
Scan List
Peak List
Anchor Scan Data
Quantification
Refinement Control
Structure Plot
Name
Info
Refine
Value
Quartz low
Scale fact...
Preferred...
B overall
Extinction
Flat Plate...
Porosity
Roughne...
Unit Cell
Atomic c...
Profile Va...
Larnite
Nonacalcium ...
Anhydrite
Gypsum
Portlandite
Brownmillerite
Dipotassium ...
Calcite
Hatrurite
Selected object: Peak(s)
Basic Properties
Shape Function
Pseudo Voigt
Split Peak
Refine Position
Refine Height
Refine FWHM
Refine Shape
Position [°2Theta]
17.67384
Height [cts]
2.13496
FWHM Left [°2Th.]
0.1
FWHM Right [°2Th.]
0
Shape Left
0.6
Shape Right
0
Integral Breadth [°2Th.]
0.27909
Area [cts*°2Th.]
0.6
d-spacing
5.01423
Sine^2 Theta
0.0236
Relative Intensity [%]
0.02231
Background [cts]
691.1251
FWHM Asymmetry Ratio
0
FWHM Asymmetry [%]
0
Shape Asymmetry Ratio
0
Shape Asymmetry [%]
0
Significance
0
Tip Width
0.12
Line Profile Analysis
More Properties
Derived from
Pure K-Alpha1